

Supporting Information for:

## Spatially-Controllable and Uniform Photochemical Transfer Printing of Block Copolymer Nanopatterns

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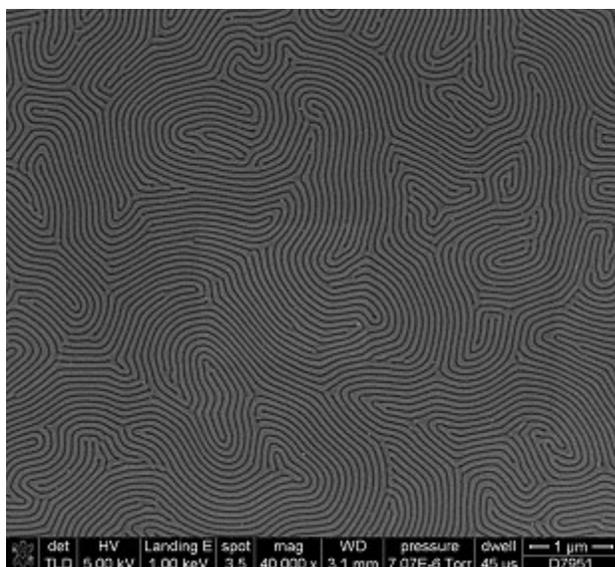


Figure S1. Representative SEM image of the Master film formed at  $L_0 = 87$  nm using 105 kDa-b-106 kDa PS-b-PMMA via a sequential solvent annealing and thermal annealing driven self-assembly process.<sup>1,2</sup>

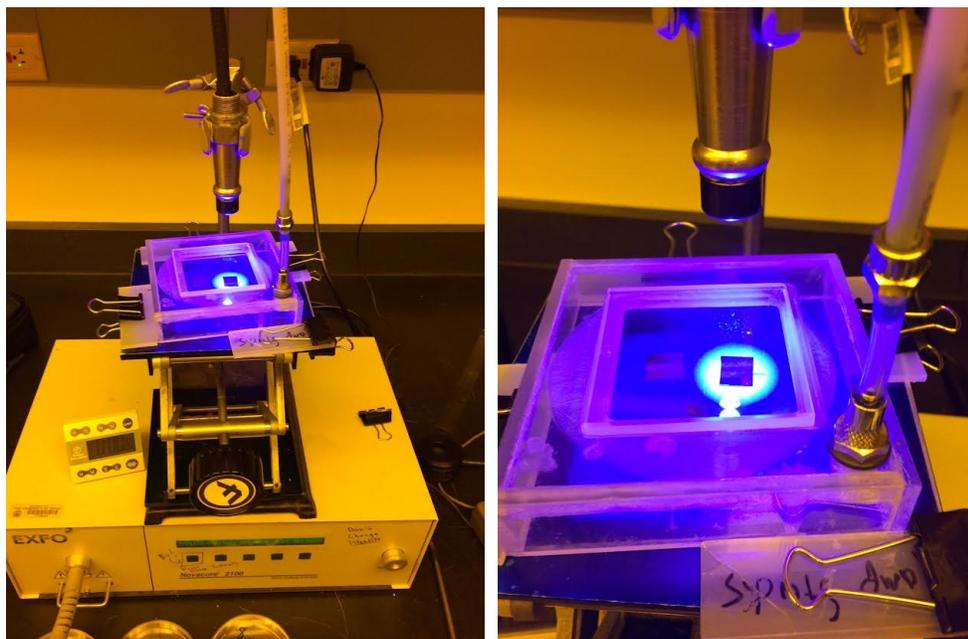


Figure S2. Photographs of the  $N_2$  purge chamber and exposure process depicted by Figure 1a; in this step PSSMA is grafted to the Master film.

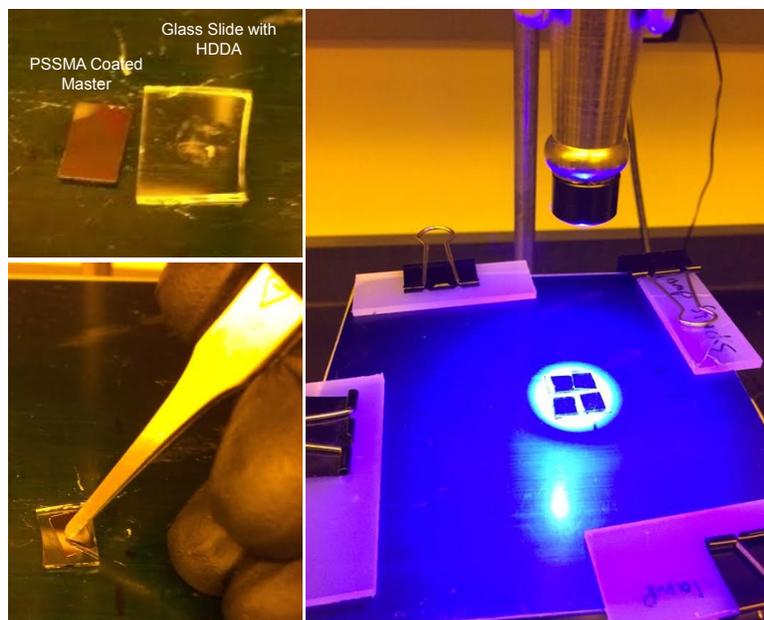


Figure S3. Photographs of the process depicted by Figure 1b; in this step the chemical nanopattern is adhered to the Replica substrate.

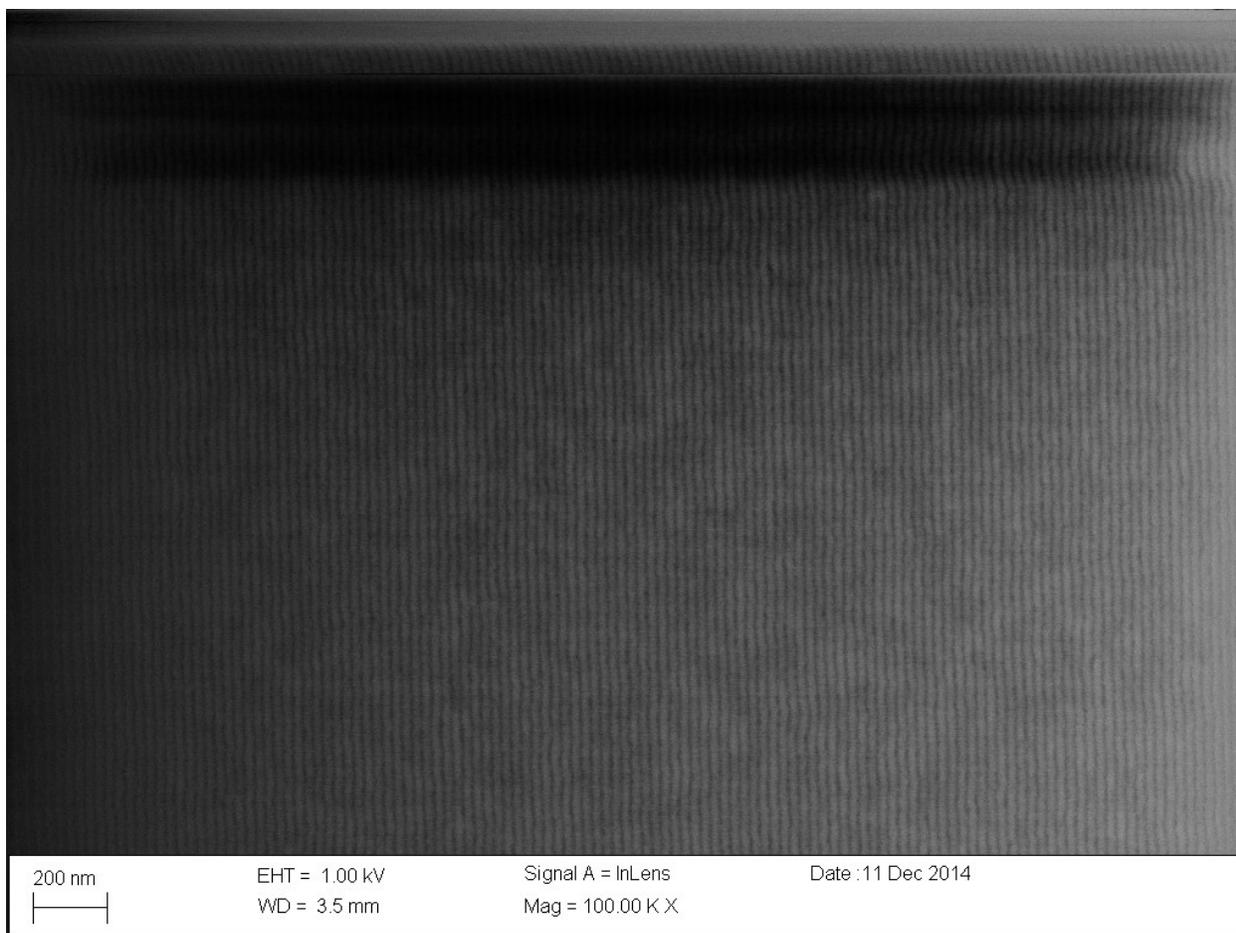


Figure S4. Unedited SEM image of the Replica sample from which the center panel of Figure 2 was excerpted. The distortion at the top of the image arises from charging artifacts of the non-conductive polymer film.

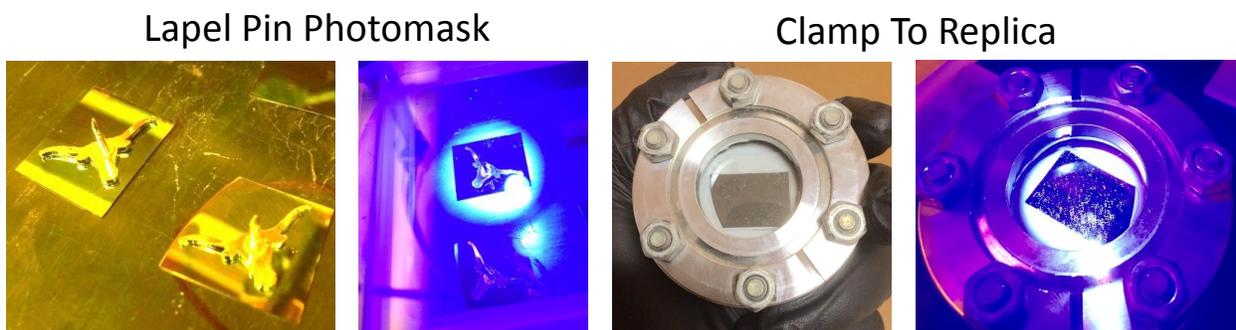


Figure S5. Photographs of the two light exposure steps used to fabricate the example of large area, spatially controlled PTP in Figure 3.

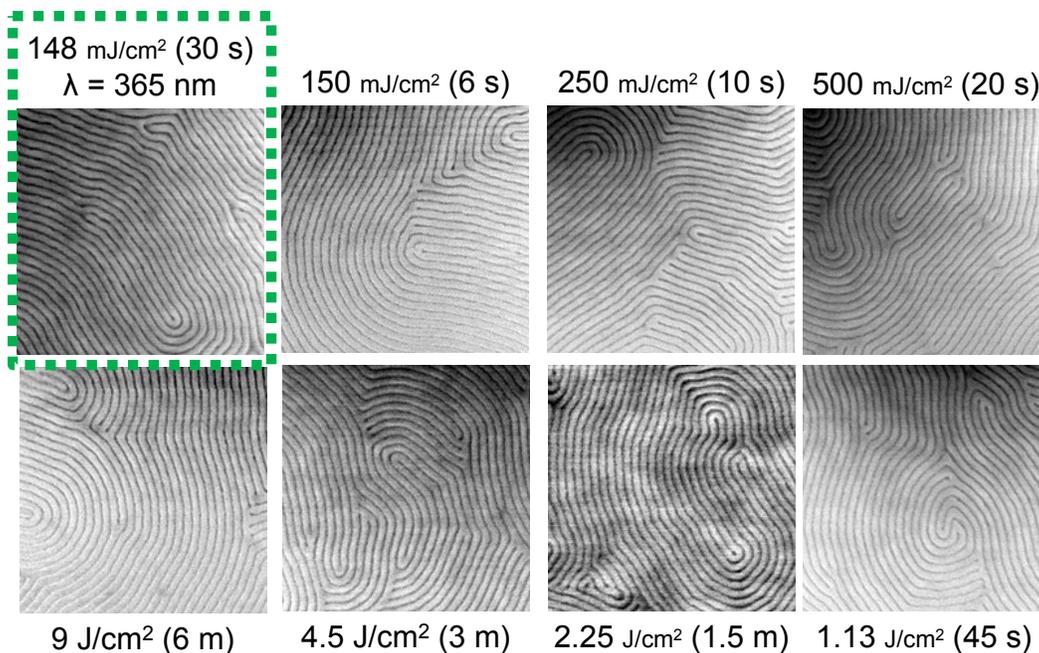


Figure S6. Representative  $1 \mu\text{m}^2$  SEM images of Replica samples in which the exposure dose used to photopolymerize the liquid conformal layer (Figure 1b) increases clockwise, starting in the upper left panel.  $L_0 = 42 \text{ nm}$  fingerprint films were used as Masters in this experiment. Note that the lowest dose listed has been passed through a  $\lambda = 365 \text{ nm}$  bandpass filter; the other samples were prepared with a broadband exposure. PTP was successful at every dose, even when using wavelengths of light that are not absorbed by PSSMA. Therefore the only critical criteria for the photoexposure step depicted in Figure 1b is that it be sufficient to photopolymerize the liquid conformal layer.

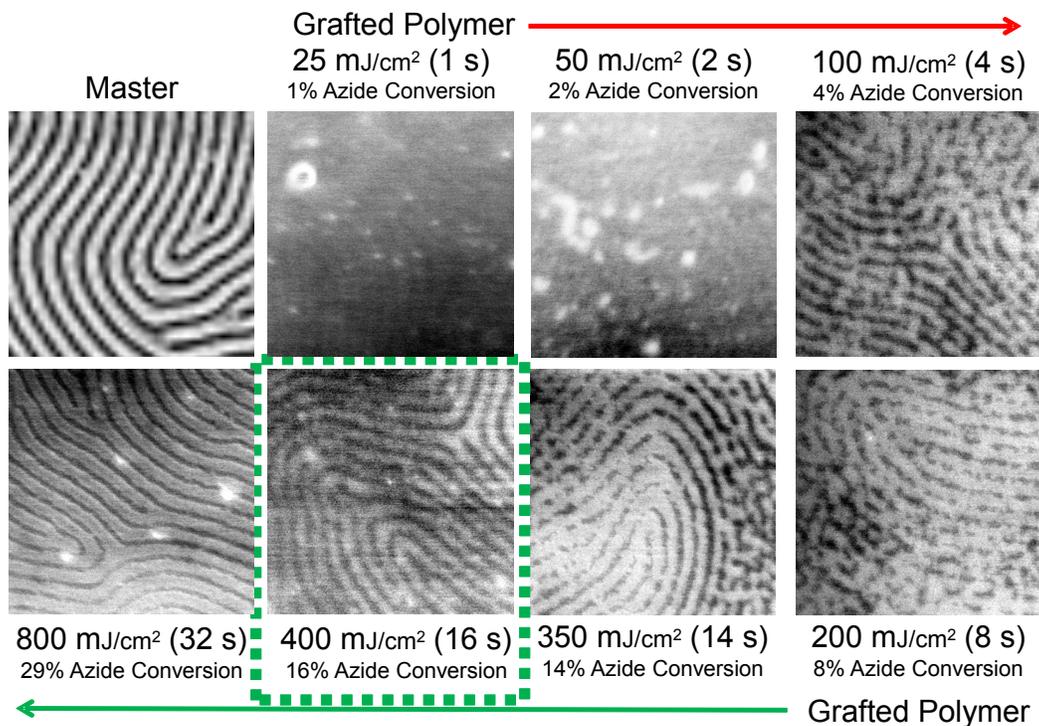


Figure S7. Representative 1  $\mu\text{m}^2$  SEM images of the  $L_0 = 87$  nm PS-b-PMMA Master film and grafted monolayers formed atop replica samples after separation, sonication, and rinsing by toluene. The broadband dose, duration of exposure, and photochemical conversion of azide groups increases clockwise and is indicated adjacent to the images. This data is intended to complement Figure 5.

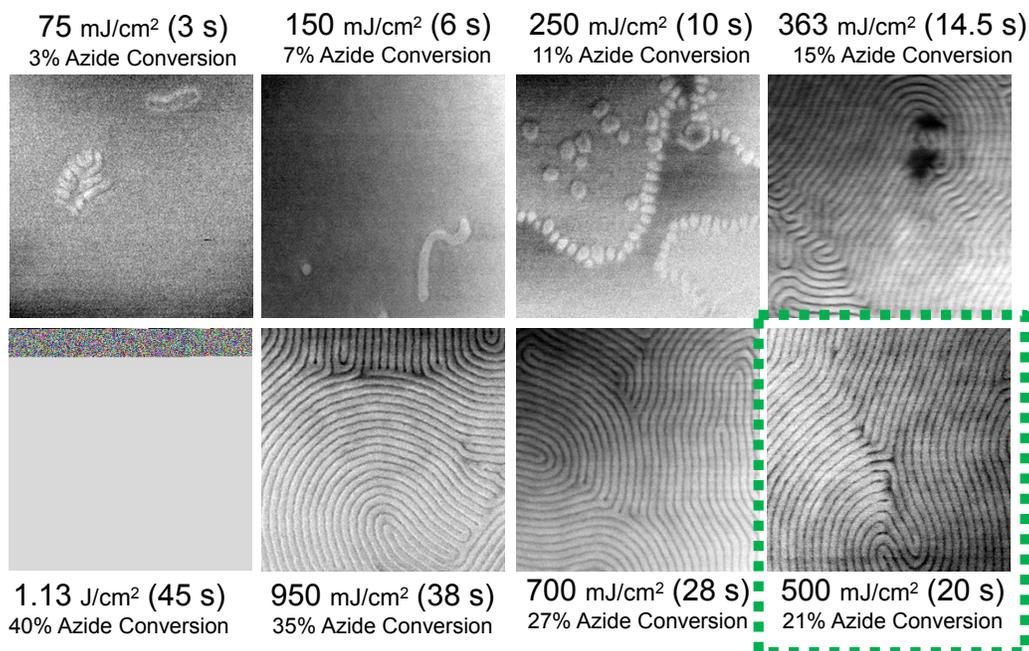


Figure S8. Representative 1  $\mu\text{m}^2$  SEM images of  $L_0 = 42$  nm PS-b-PMMA patterns formed atop Replica samples after spin-coating and annealing of a  $1L_0$  thick reassembly layer atop them. The broadband dose, duration of exposure, and photochemical conversion of azide groups increases clockwise and is indicated adjacent to the images. This data is intended to complement Figure 6.

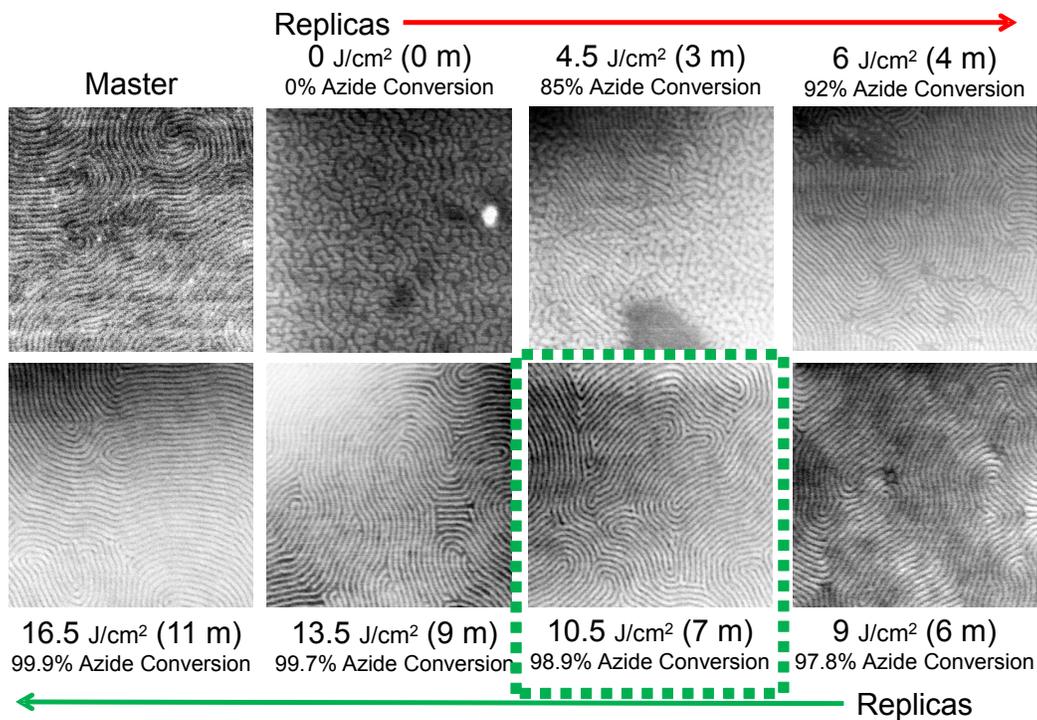


Figure S9. Representative 1  $\mu\text{m}^2$  SEM images of  $L_0 = 28$  nm PS-b-PMMA Master film and Replica samples made using PTP. The broadband dose, duration of exposure, and photochemical conversion of azide groups increases clockwise and is indicated adjacent to the images. This data is intended to complement Figure 7.

### Works Cited

1. R. P. Kingsborough, R. B. Goodman, K. Krohn and T. H. Fedynyshyn, *Proc. SPIE*, 2009, **7271**, 72712D-72712D-72710.
2. E. Kim, H. Ahn, S. Park, H. Lee, M. Lee, S. Lee, T. Kim, E.-A. Kwak, J. H. Lee, X. Lei, J. Huh, J. Bang, B. Lee and D. Y. Ryu, *ACS Nano*, 2013, **7**, 1952-1960.